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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : James Ma  
Serial No. : 10/630,543  
Filed : July 29, 2003  
Title : TRANSFER OF DIGITAL DATA ACROSS ASYNCHRONOUS CLOCK  
DOMAINS

Art Unit : 2819  
Examiner : Unknown

MAIL STOP AMENDMENT  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Copies of the references listed on the attached form PTO-1449 are enclosed.

This statement is being filed after a first Office action on the merits, but before receipt of a final Office action or a Notice of Allowance. A check for \$180 in payment of the late submission fee of C.F.R. § 1.17(p) is enclosed. Please apply any other charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: 21 December, 2004

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I hereby certify under 37 CFR §1.8(a) that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage on the date indicated below and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

December 21, 2004  
Date of Deposit

Leticia Hernandez  
Signature

Leticia Hernandez  
Typed or Printed Name of Person Signing Certificate

Substitute Form PTO-1449  
(Modified)U.S. Department of Commerce  
Patent and Trademark OfficeAttorney's Docket No.  
15758-003001Application No.  
10/630,543**Information Disclosure Statement  
by Applicant**

(Use several sheets if necessary)

Applicant  
James MaFiling Date  
July 29, 2003Group Art Unit  
2819**U.S. Patent Documents**

| Examiner Initial | Desig. ID | Document Number | Publication Date | Patentee | Class | Subclass | Filing Date If Appropriate |
|------------------|-----------|-----------------|------------------|----------|-------|----------|----------------------------|
|                  |           |                 |                  |          |       |          |                            |
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**Foreign Patent Documents or Published Foreign Patent Applications**

| Examiner Initial | Desig. ID | Document Number | Publication Date | Country or Patent Office | Class | Subclass | Translation |    |
|------------------|-----------|-----------------|------------------|--------------------------|-------|----------|-------------|----|
|                  |           |                 |                  |                          |       |          | Yes         | No |
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**Other Documents (include Author, Title, Date, and Place of Publication)**

| Examiner Initial | Desig. ID | Document   |
|------------------|-----------|--|
|                  | AV        | ICT paper entitled "PEEL™ Device Metastability"; date unknown but known to be before June 10, 2003; 3 pp   |
|                  | AW        | Semiati, et al., "Timing Measurements of Synchronization Circuits," VLSI Systems Research Center, Technion – Israel Institute of Technology, Haifa, Israel; May 2003; 10 pp  |
|                  | AX        | Varma, et al., "Metastability Reduction by Aperture Transformation," IBM India Research Laboratory, Centre for Applied Research Electronics, New Delhi, India; date unknown but known to be before June 10, 2003; 10pp |

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.